

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Hisashi Ohtani et al. Art Unit : 2815
 Serial No. : 09/379,702 Examiner : Eugene Lee
 Filed : August 24, 1999 Conf. No. : 1613
 Title : METHOD OF FABRICATING SEMICONDUCTOR DEVICES

MAIL STOP AF

Commissioner for Patents
 P.O. Box 1450
 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached pto-1449 form.

Submitted herewith is an English translation of the following foreign language references, or portions thereof:

Desig. ID	Source
AN	Japan 03-004564 – English Abstract: esp@cenet.com .
AO	Japan 06-296020 – English Abstract: esp@cenet.com and family to U.S. Patent No. 5,608,232 (Desig. ID “AA”), U.S. Patent No. 5,639,698 (Desig. ID “AB”), U.S. Patent No. 5,897,347 (Desig. ID “AD”), U.S. Patent No. 5,956,579 (Desig. ID “AE”), U.S. Patent No. 6,084,247 (Desig. ID “AF”), U.S. Patent No. 6,997,985 (Desig. ID “AG”), European Patent Application No. 0 612 102 (Desig. ID “AL”) and European Patent Application No. 1 119 053 (Desig. ID “AM”).
AP	Japan 07-226374 – English Abstract: esp@cenet.com .
AQ	Japan 08-031737 – English Abstract: esp@cenet.com and family to U.S. Patent No. 5,851,860 (Desig. ID “AC”).

This statement is being filed after a final office action or a notice of allowance, but before payment of the issue fee. Each item of information in this statement, with the exception of references “AA” through “AG”, “AL” and “AM”, (i) was cited in a communication from a foreign patent office in a counterpart foreign application, the communication being dated November 7, 2006, which is not more than three months prior to the filing of this statement, and (ii) was not first cited in any communication from a foreign patent office in a counterpart application which was more than three months prior to the filing date of this statement. Reference “AA” through “AG”, “AL” and “AM” are English-language documents

corresponding to references "AO" and "AQ", as set forth above, and are cited in accordance with MPEP 609(III)(B)(5).

The \$180 late submission fee under §1.17(p) is being paid concurrently herewith on the Electronic Filing System (EFS) by way of Deposit Account authorization. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 12/8/06



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40383842.doc

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-093002	Application No. 09/379,702
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Hisashi Ohtani et al.	
		Filing Date August 24, 1999	Group Art Unit 2815
(37 CFR §1.98(b))			

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,608,232	03/04/1997	YAMAZAKI et al.			06/05/1995
	AB	5,639,698	06/17/1997	YAMAZAKI et al.			02/15/1994
	AC	5,851,860	12/22/1998	MAKITA et al.			06/02/1995
	AD	5,897,347	04/27/1999	YAMAZAKI et al.			09/24/1996
	AE	5,956,579	09/21/1999	YAMAZAKI et al.			07/15/1997
	AF	6,084,247	07/04/2000	YAMAZAKI et al.			12/18/1996
	AG	6,997,985	02/14/2006	YAMAZAKI et al.			12/18/1996
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	AL	EP0 612 102	08/24/1994	EUROPE			In English	
	AM	EP1 119 053	07/25/2001	EUROPE			In English	
	AN	JP03-004564	01/10/1991	JAPAN			Abstract	
	AO	JP06-296020	10/21/1994	JAPAN			Abstract	
	AP	JP07-226374	08/22/1995	JAPAN			Abstract	
	AQ	JP08-031737	02/02/1996	JAPAN			Abstract	

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AR	
	AS	
	AT	
	AU	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	